



Supporting Information

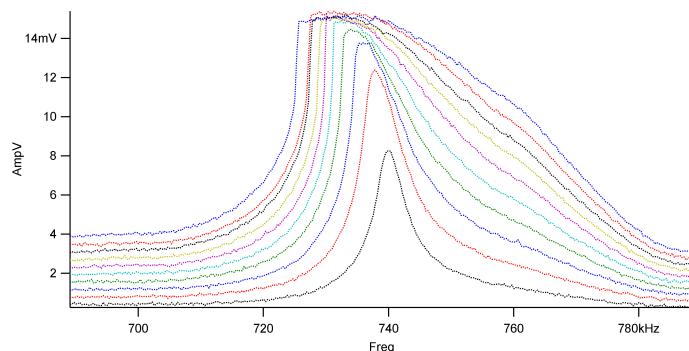
for

Cantilever signature of tip detachment during contact resonance AFM

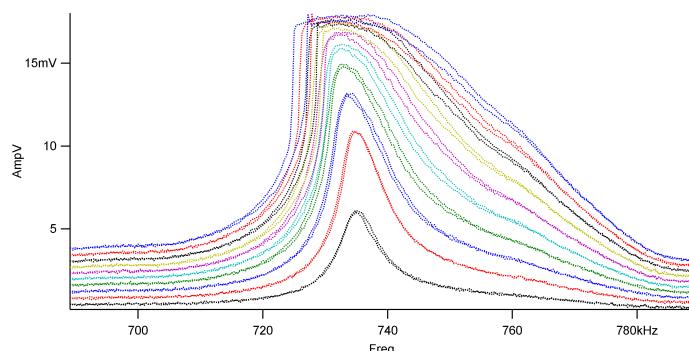
Devin Kalafut, Ryan Wagner, Maria Jose Cadena, Anil Bajaj and Arvind Raman

Beilstein J. Nanotechnol. **2021**, 12, 1286–1296. doi:10.3762/bjnano.12.96

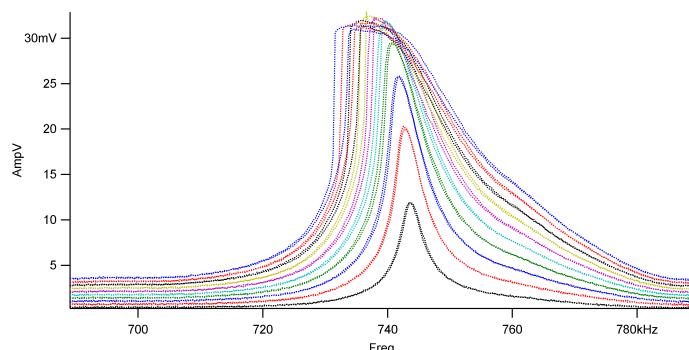
Additional AFM measurements



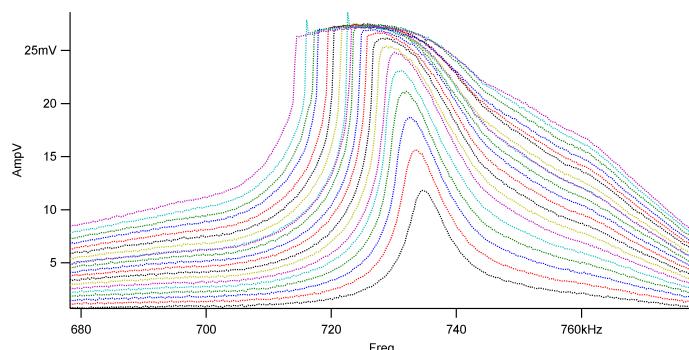
(a)



(b)



(c)



(d)

Figure S1: Additional evidence of tip-sample detachment on silicon samples at various piezoelectric drive amplitudes, shown as photodiode detector amplitude vs drive frequency.